1 day workshop on FIB SEM

Enabling breakthrough innovations with DualBeam technology—faster and easier than ever before

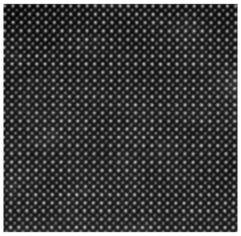
Introduction

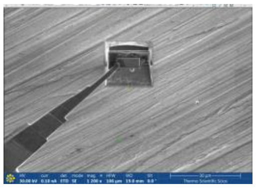
The world faces increased demand for more efficient transportation, enhanced solutions for clean energy, and original synthetically engineered materials. These demands drive research and development to produce materials that are reliable and better performing. Consequently, materials scientists face complex analytical tasks to support this global demand.

Thermo Scientific™ FIB-SEMs provide nanometer-scale data about a material by various combinations of the precise sample modification of the FIB and the high-resolution imaging of the SEM. DualBeam instruments provide high-resolution imaging with high materials contrast; fast, easy, precise, high-quality sample preparation for (S)TEM imaging and atom probe tomography (APT), and high-quality subsurface and 3D characterization.

One-day workshop on Helios 5 UX

We cordially invite you to join us for a 1-day workshop on Helios 5 UX DualBeam installed at Centre for NanoScience and Engineering (CeNSE) IISc Bangalore.

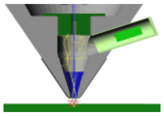




Workshop modules

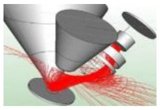
- **Optimization of Helios imaging detectors**
- **TEM sample preparation using AutoTEM**
- **Patterning using Nanobuilder.**

SEM-TLD



STEM 3+

FIB-ICE



To confirm your attendance, kindly register by filling out the form available at the following link before 5th Dec 2023
https://forms.office.com/r/XTzaX4QbrF

or SCAN the QR code below

Program Schedule

Date	Time	Topic	Speaker
08th Dec	10.00 am-12.30 pm	Introduction to FIB-SEM and Applications to the semiconductor industry	Dr Karthick Balasubramanian, Sales Development Manager Thermo Fisher Scientific
08th Dec	2.00 pm -05.00 pm	Live demo	Mr. Devan Liu Application Specialist Thermo Fisher Scientific

30 years of DualBeam™ innovations